



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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企业微信二维码



企业QQ二维码

Product Summary

BV _{DSS}	R _{DS(ON)} Max	I _D T _C = +25°C
100V	14.5mΩ @ V _{GS} = 10V	56A
	19.5mΩ @ V _{GS} = 6V	49A

Description and Applications


This MOSFET is designed to meet the stringent requirements of automotive applications. It is AEC-Q101 qualified, supported by a PPAP, and is ideal for use in:

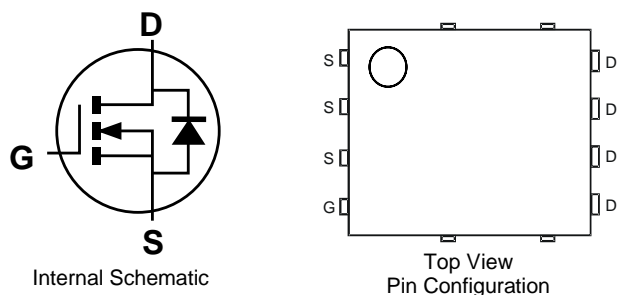
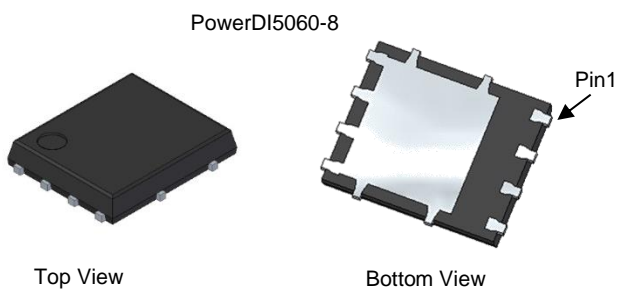
- Motor controls
- DC-DC converters
- Power managements

Features and Benefits

- Rated to +175°C – Ideal for High Ambient Temperature Environments
- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- Thermally Efficient Package – Cooler Running Applications
- Low R_{DS(ON)} – Minimizes On-State Losses
- Low Input Capacitance
- Fast Switching Speed

Mechanical Data

- Package: PowerDI[®]5060-8
- Package Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See Diagram
- Terminals: Finish – Matte Tin Annealed over Copper Lead-Frame. Solderable per MIL-STD-202, Method 208 
- Weight: 0.097 grams (Approximate)



Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current (Note 5) $V_{GS} = 10\text{V}$	I_D	56	A
Steady State		39	
Pulsed Drain Current (10 μs Pulse, Duty Cycle = 1%)	I_{DM}	120	A
Maximum Continuous Body Diode Forward Current (Note 5)	I_S	56	A
Avalanche Current, $L = 3\text{mH}$	I_{AS}	7.5	A
Avalanche Energy, $L = 3\text{mH}$	E_{AS}	85	mJ
Avalanche Current, $L = 0.1\text{mH}$	I_{AS}	15.8	A
Avalanche Energy, $L = 0.1\text{mH}$	E_{AS}	12.5	mJ

Thermal Characteristics

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 6)	P_D	2.7	W
Thermal Resistance, Junction to Ambient (Note 6)	$R_{\theta JA}$	55	$^\circ\text{C/W}$
Total Power Dissipation (Note 5)	P_D	94	W
Thermal Resistance, Junction to Case (Note 5)	$R_{\theta JC}$	1.6	$^\circ\text{C/W}$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +175	$^\circ\text{C}$

Electrical Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV_{DSS}	100	—	—	V	$V_{GS} = 0\text{V}, I_D = 1\text{mA}$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	1	μA	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	$V_{GS(TH)}$	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	11.3	14.5	m Ω	$V_{GS} = 10\text{V}, I_D = 20\text{A}$
		—	14.7	19.5		$V_{GS} = 6\text{V}, I_D = 20\text{A}$
Diode Forward Voltage	V_{SD}	—	0.9	1.3	V	$V_{GS} = 0\text{V}, I_S = 20\text{A}$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C_{iss}	—	2343	—	pF	$V_{DS} = 50\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$
Output Capacitance	C_{oss}	—	487	—		
Reverse Transfer Capacitance	C_{rss}	—	26	—		
Gate Resistance	R_G	—	0.69	—	Ω	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$
Total Gate Charge	Q_G	—	30.1	—	nC	$V_{DD} = 50\text{V}, I_D = 10\text{A},$ $V_{GS} = 10\text{V}$
Gate-Source Charge	Q_{GS}	—	7.5	—		
Gate-Drain Charge	Q_{GD}	—	6.5	—		
Turn-On Delay Time	$t_{D(ON)}$	—	9.8	—	ns	$V_{DD} = 50\text{V}, V_{GS} = 10\text{V},$ $I_D = 10\text{A}, R_G = 6\Omega$
Turn-On Rise Time	t_R	—	7.8	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	22.5	—		
Turn-Off Fall Time	t_F	—	9.6	—		
Reverse Recovery Time	t_{RR}	—	43.1	—	ns	$I_F = 10\text{A}, di/dt = 100\text{A}/\mu\text{s}$
Reverse Recovery Charge	Q_{RR}	—	65.1	—	nC	

- Notes:
- Thermal resistance from junction to soldering point (on the exposed drain pad).
 - Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
 - Short duration pulse test used to minimize self-heating effect.
 - Guaranteed by design. Not subject to product testing.

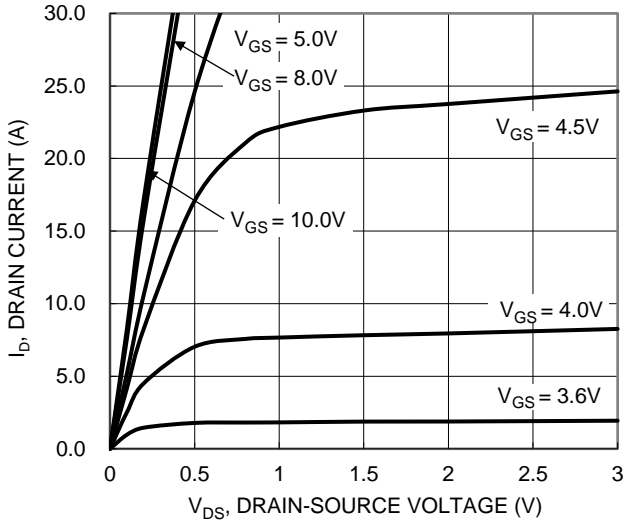


Figure 1. Typical Output Characteristic

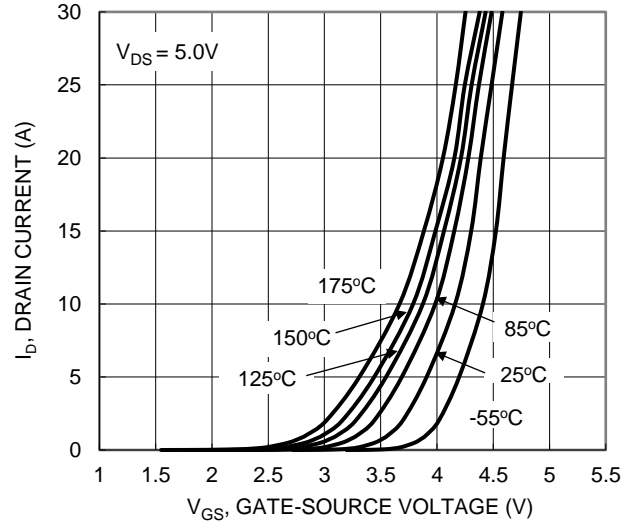


Figure 2. Typical Transfer Characteristic

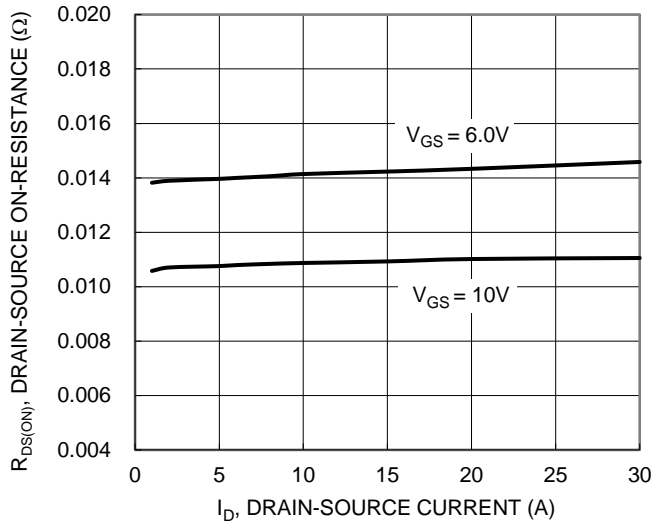


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

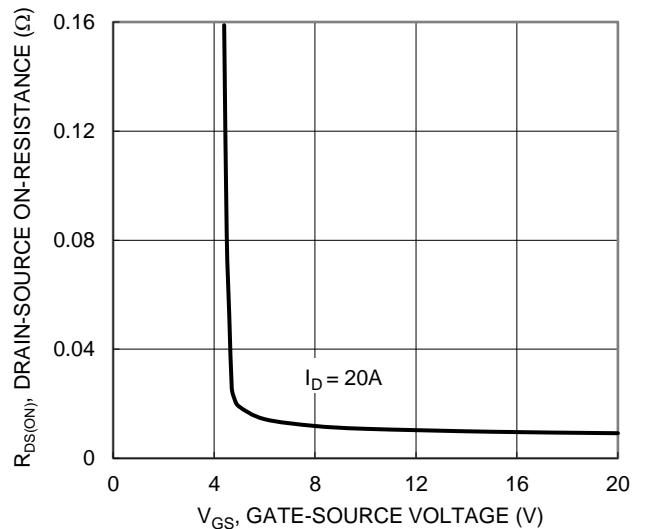


Figure 4. Typical Transfer Characteristic

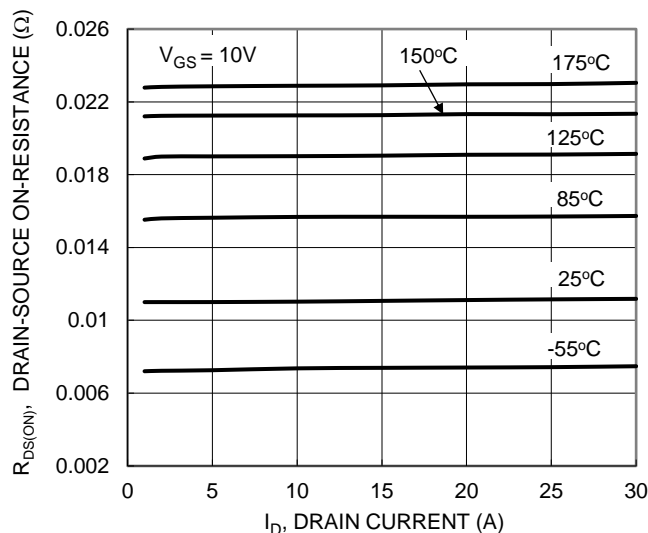


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

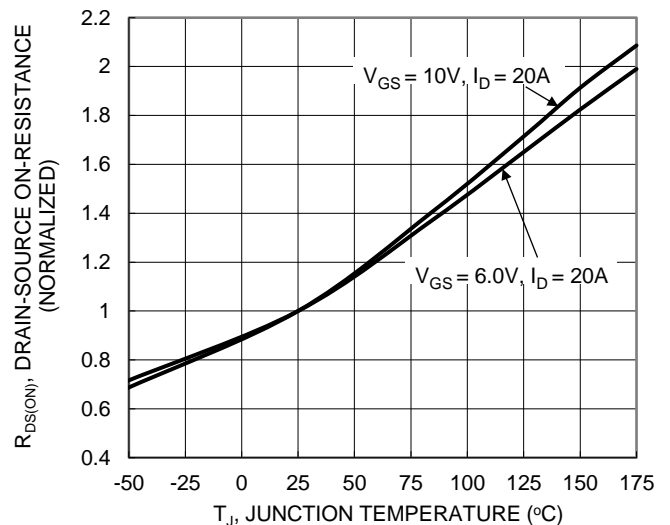


Figure 6. On-Resistance Variation with Temperature

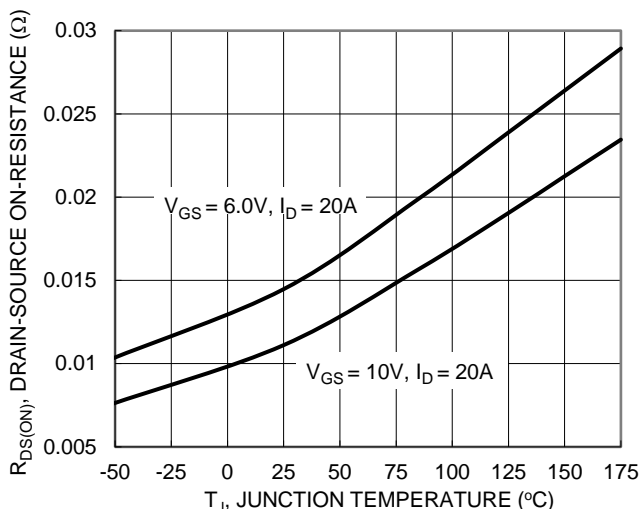


Figure 7. On-Resistance Variation with Temperature

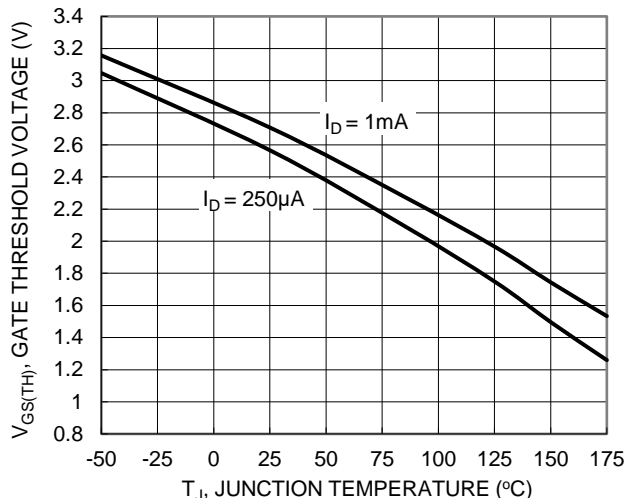


Figure 8. Gate Threshold Variation vs. Junction Temperature

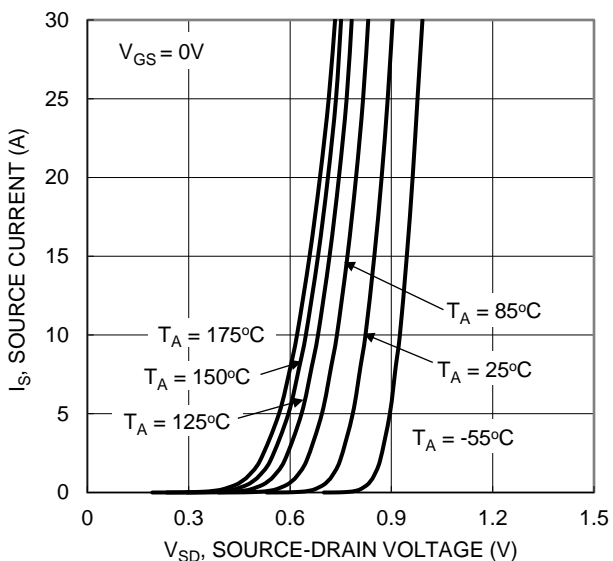


Figure 9. Diode Forward Voltage vs. Current

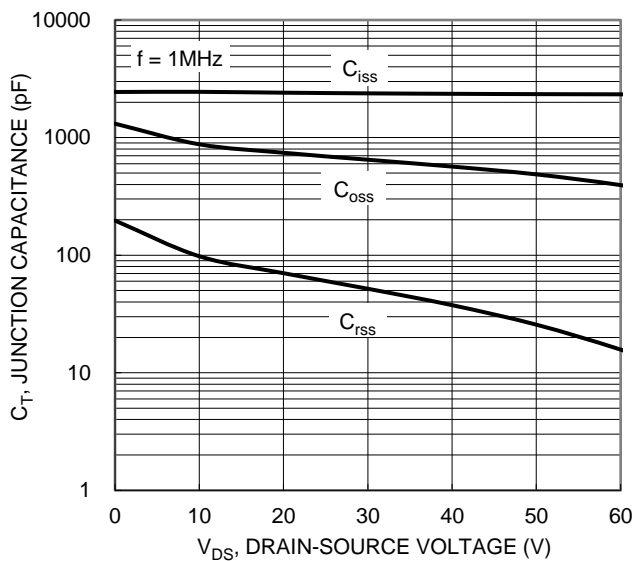


Figure 10. Typical Junction Capacitance

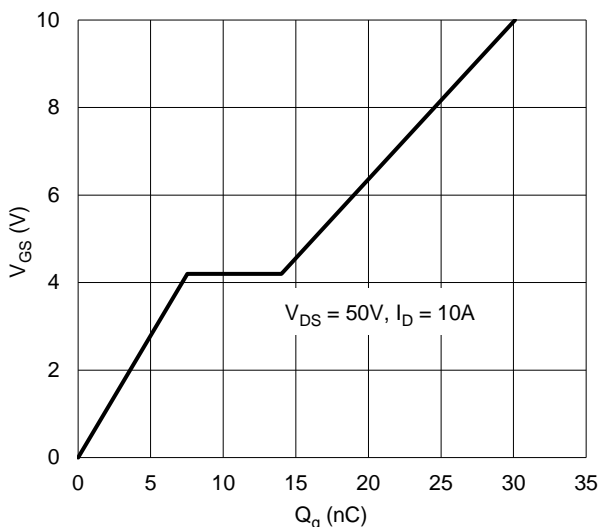


Figure 11. Gate Charge

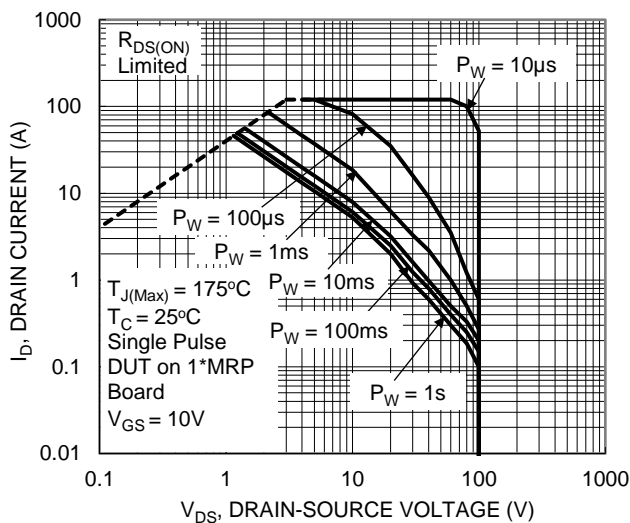


Figure 12. SOA, Safe Operation Area

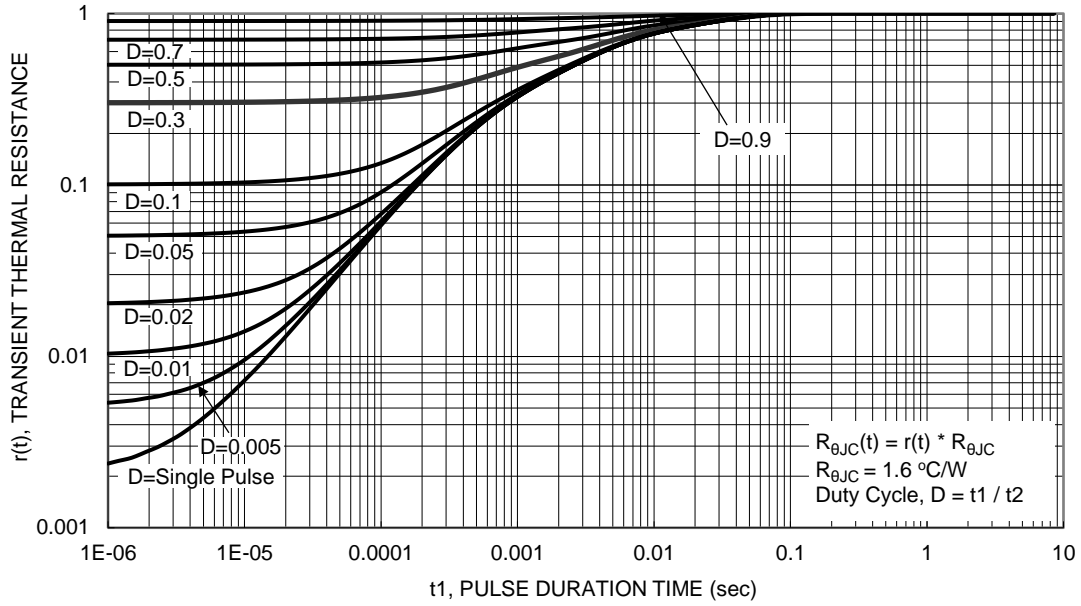
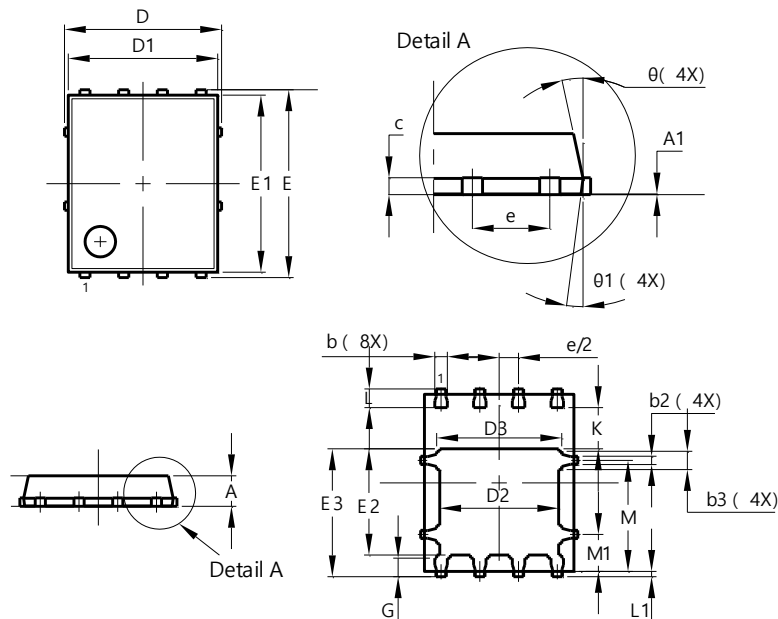


Figure 13. Transient Thermal Resistance

Package Outline Dimensions

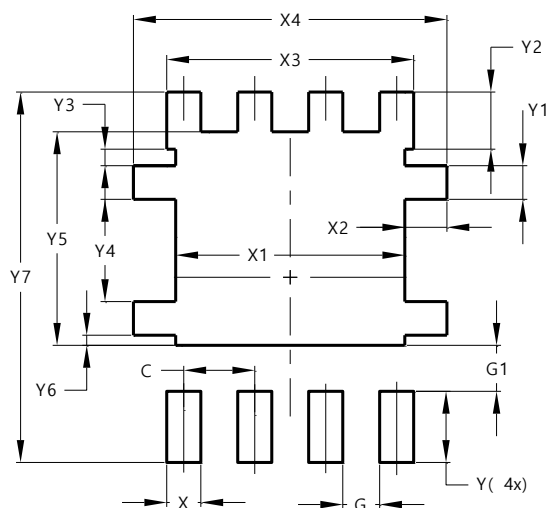
PowerDI5060-8



PowerDI5060-8			
Dim	Min	Max	Typ
A	0.90	1.10	1.00
A1	0.00	0.05	-
b	0.33	0.51	0.41
b2	0.200	0.350	0.273
b3	0.40	0.80	0.60
c	0.230	0.330	0.277
D	5.15 BSC		
D1	4.70	5.10	4.90
D2	3.70	4.10	3.90
D3	3.90	4.30	4.10
E	6.15 BSC		
E1	5.60	6.00	5.80
E2	3.28	3.68	3.48
E3	3.99	4.39	4.19
e	1.27 BSC		
G	0.51	0.71	0.61
K	0.51	-	-
L	0.51	0.71	0.61
L1	0.100	0.200	0.175
M	3.235	4.035	3.635
M1	1.00	1.40	1.21
θ	10°	12°	11°
$\theta1$	6°	8°	7°
All Dimensions in mm			

Suggested Pad Layout

PowerDI5060-8



Dimensions	Value (in mm)
C	1.270
G	0.660
G1	0.820
X	0.610
X1	4.100
X2	0.755
X3	4.420
X4	5.610
Y	1.270
Y1	0.600
Y2	1.020
Y3	0.295
Y4	1.825
Y5	3.810
Y6	0.180
Y7	6.610